

1. Record Nr.	UNINA9910437805603321
Autore	Joy David C
Titolo	Helium ion microscopy : principles and applications // David C. Joy
Pubbl/distr/stampa	New York : , : Springer, , 2013
ISBN	1-4614-8660-2
Edizione	[1st ed. 2013.]
Descrizione fisica	1 online resource (viii, 64 pages) : illustrations (some color)
Collana	SpringerBriefs in Materials, , 2192-1091
Disciplina	578.1 620.11
Soggetti	Field ion microscopy Helium ions Ion bombardment
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	"ISSN: 2192-1091."
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Chapter 1: Introduction to Helium Ion Microscopy -- Chapter 2: Microscopy with Ions - A brief history -- Chapter 3: Operating the Helium Ion Microscope -- Chapter 4: Ion –Solid Interactions and Image Formation -- Chapter 5: Charging and Damage -- Chapter 6: Microanalysis with the HIM -- Chapter 7: Ion Generated Damage -- Chapter 8: Working with other Ion beams -- Chapter 9: Patterning and Nanofabrication -- Conclusion -- Bibliography -- Appendix: iSE Yields, and IONiSE parameters for He+ excitation of Elements and Compounds -- Index.
Sommario/riassunto	Helium Ion Microscopy: Principles and Applications describes the theory and discusses the practical details of why scanning microscopes using beams of light ions – such as the Helium Ion Microscope (HIM) – are destined to become the imaging tools of choice for the 21st century. Topics covered include the principles, operation, and performance of the Gaseous Field Ion Source (GFIS), and a comparison of the optics of ion and electron beam microscopes including their operating conditions, resolution, and signal-to-noise performance. The physical principles of Ion-Induced Secondary Electron (iSE) generation by ions are discussed, and an extensive database of iSE yields for many elements and compounds as a function of incident ion species and its energy is included. Beam damage and charging are frequently

outcomes of ion beam irradiation, and techniques to minimize such problems are presented. In addition to imaging, ions beams can be used for the controlled deposition, or removal, of selected materials with nanometer precision. The techniques and conditions required for nanofabrication are discussed and demonstrated. Finally, the problem of performing chemical microanalysis with ion beams is considered. Low energy ions cannot generate X-ray emissions, so alternative techniques such as Rutherford Backscatter Imaging (RBI) or Secondary Ion Mass Spectrometry (SIMS) are examined. Serves as a concise but authoritative introduction to the latest innovation in scanning microscopy Compares ion and electron beams as options for microscopy Presents a detailed physical model of ion-solid interactions and signal generation Provides a detailed database of iSE yield behavior as a function of the target ion, element, and energy.

2. Record Nr.	UNINA9910955440303321
Autore	Harris James <1957->
Titolo	Fractal architecture : organic design philosophy in theory and practice / James Harris
Pubbl/distr/stampa	Albuquerque [N.M.] , : University of New Mexico Press, 2012
ISBN	9781283741637 1283741636 9780826352026 0826352022
Edizione	[1st ed.]
Descrizione fisica	1 online resource (424 p.)
Disciplina	704.9 704.9/49514742 720.1
Soggetti	Geometry in architecture Fractals
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Front Cover; Title Page; Copyright; Contents; Introduction; Part I: Man,

Nature, and Architecture; 1: The Journey from Mathematical Monsters to the Key to Nature's Structure; 2: The Human Desire for Nature; 3: Nature's Order and Its Architectural Embodiment; 4: Skyscraper Form and Its Fractal Derivative; Part II: Nature and Human Cognition; 5: Gestalt and the Wholeness of Fractal Structure; 6: Perception and Cognition of Natural Form; 7: The Universal Quality of Fractal Expression; 8: The Abstract Trajectory to the Fractal Modernist Form; Part III: Architecture from Nature  
9: Nature's Generative Character10: Elements of Fractal Form; 11: The Fractal Confluence of Science and Art; 12: The Spectrum of Architecture's Relationship to Nature; Notes; Selected Bibliography; Index; Back Cover

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## Sommario/riassunto

In *Fractal Architecture*, architect James Harris presents a definitive, lavishly illustrated guide that explains both the "how" and "why" of incorporating fractal geometry into architectural design.

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